

Brian E. Cron

Title:

Methods for Conditioning Surfaces of Polishing Pads After

**Chemical-Mechanical Polishing** 

Assignee:

Micron Technology, Inc.

Serial No.:

10/705,371

Filed:

November 10, 2003 [RCE Filed Herewith]

## INFORMATION DISCLOSURE STATEMENT

## PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98

The attached Form PTO-1449 is submitted in compliance with 37 CFR §1.56. Pursuant to FEDERAL REGISTER, Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. No admission is made regarding whether the listed references are prior art.

Citation of these references is respectfully requested.

Date:

Attorney:

David G. Latwesen, Ph.D.

Respectfully submitted,

Reg. No. 38,533 Wells St. John P.S.

Form PT 0419P PATENT A (Use several sheets if necessary)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-2430

SERIAL NO. 10/705,371

**APPLICANT** Brian E. Cron

FILING DATE Nov. 10, 2003 [RCE filed herewith]

GROUP 3723

				U.S. PATENT DOCUMENTS				
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Fili If Ap	ng Date propriate
	AA	6,740,247 B1	05/04	Han et al.			_	
	AB	6,776,691 B2	08/04	Nishimura et al.				-
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## HIS PATENT DOCUMENTS

. +6				U.S. PATENT DOCUMENTS				
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Fili If Ap	ng Date propriate
	AA	2003/0217762 A	A1 11/03	Kobayashi et al.				
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